



Recent results on micro-electronics  
developments for future trackers in  
Hi-Lumi upgrades

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*on behalf of the IGNITE collaboration*



# Challenges in next Hi-Lumi upgrades (and 4D tracking)

Future colliders (LHCb Upgrade II, HIKE (NA62 upgrade), CMS-PPS, ATLAS AFP, FCC-hh) will have to cope with extremely high instantaneous luminosity:

## ■ REQUIREMENTS FOR SENSORS:

- Radiation hardness against fluences from  $10^{16}$  to  $10^{17} \text{ 1MeV} \frac{n_{eq}}{\text{cm}^2}$
- Spatial resolution  $\sigma_s \approx 10 \mu\text{m}$
- Time resolution  $\sigma_t \leq 50 \text{ ps}$  per hit
- Detection efficiency  $\epsilon > 99\%$  per layer

## ■ REQUIREMENTS FOR READ-OUT ELECTRONICS:

- Pixel pitch  $\approx 50 \mu\text{m}$
- Time resolution  $\sigma_t \leq 50 \text{ ps}$  on the full chain  $\rightarrow \sigma_t^2 \sim \sigma_{sensor}^2 + \sigma_{AFE}^2 + \sigma_{TDC}^2$
- Radiation hardness  $TID > 1 \text{ Grad}$
- Power budget per pixel  $P \approx 25 \mu\text{W}$  (referred to  $55 \mu\text{m}$  pitch,  $1.5 \text{ W/cm}^2$ )
- DATA BANDWIDTH  $\approx 100 \text{ Gbps/ASIC}$

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**CMOS 28-nm  
ELECTRONICS**

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**CMOS 28-nm  
ELECTRONICS**

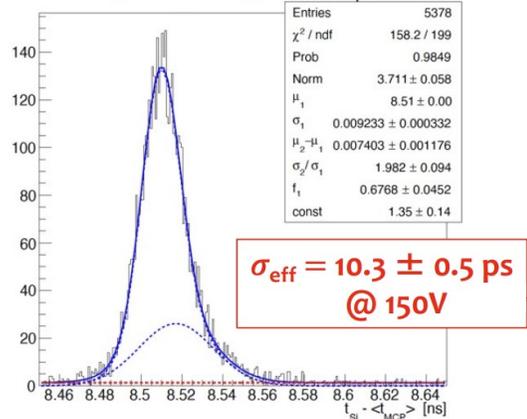


**SILICON  
PHOTONICS**

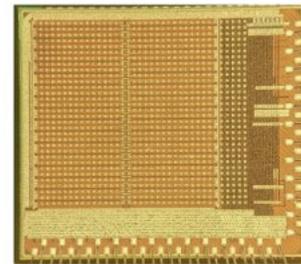
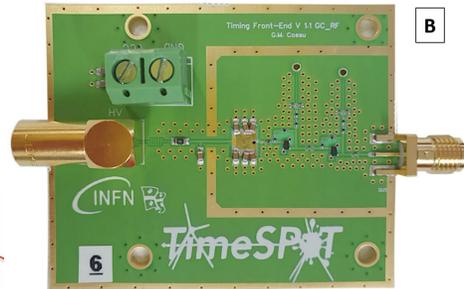
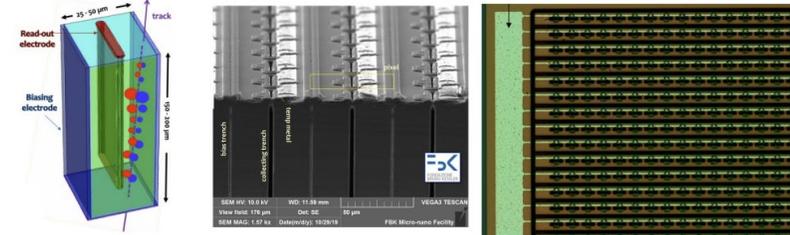


P. I. Adriano Lai

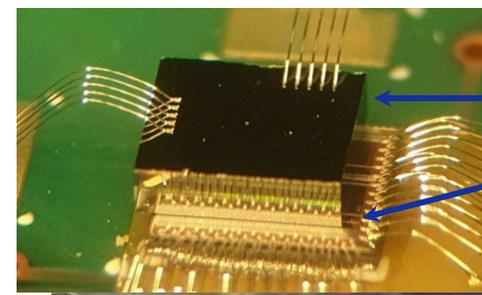
Irradiated @  $2.5 \cdot 10^{16} \text{ n}_{eq}/\text{cm}^2$ ,  $\alpha_{tilt} = 0^\circ$



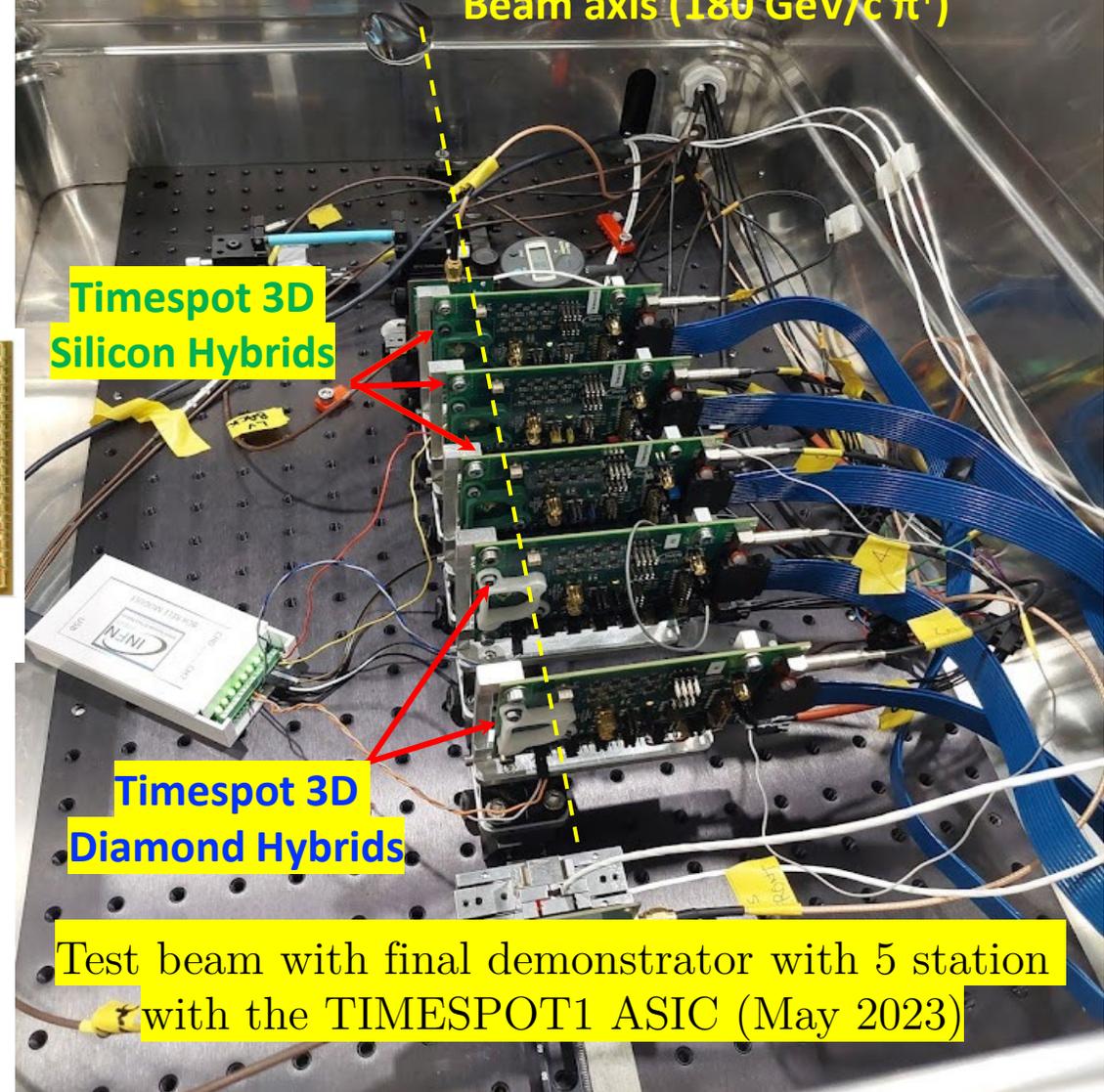
## 1. DESIGN AND FABRICATION OF 3D DETECTOR (Silicon and Diamond)



Timespot1 ASIC



Sensor matrix integrated electronics



Beam axis ( $180 \text{ GeV}/c \pi^+$ )

Timespot 3D Silicon Hybrids

Timespot 3D Diamond Hybrids

Test beam with final demonstrator with 5 station with the TIMESPOT1 ASIC (May 2023)

10ps time resolution with 3D trench sensors and custom discrete electronics measured at test beam facility also on irradiated sensor up to fluence  $2.5 \cdot 10^{16} \text{ 1 MeV n}_{eq}/\text{cm}^2$  see [A. Lai presentation Vertex 2022](#) And Gian-Franco Dalla Betta's Talk [Timing performance of 3D silicon sensor](#)

See POSTER: **Intrinsic timing properties of simulated ideal 3D-trench silicon sensor with fast front-end electronics** GM Cossu, D Brundu, A Lai

# Falaphel

## FAST LINK AND RAD-HARD FRONT-END WITH INTEGRATED PHOTONICS AND ELECTRONICS FOR PHYSICS

P. I. Fabrizio Palla

Compact Silicon Photonic Mach-Zehnder Modulators for High-Energy Physics

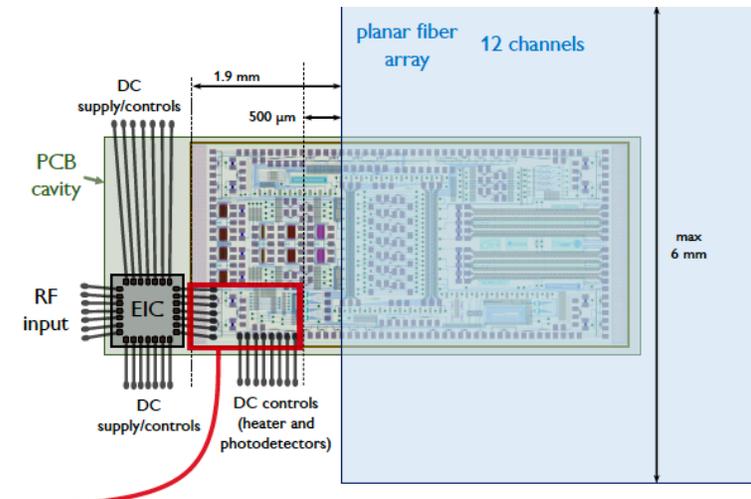
[See Simone Cammarata's talk given at TWEEN 2023](#)

25 Gb/s NRZ transmission validated using standard Folded Mach Zehnder Modulator (FMZM) and RAD HARD FMZM up to 1.25 Grad!

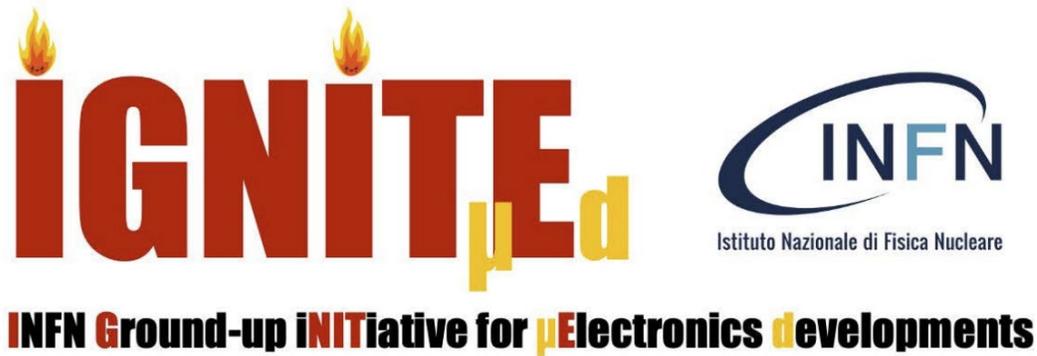
### Also developing:

28-nm CMOS Serializer (target data rate 25 Gbps)

28-nm CMOS Driver/Receiver (target data rate 25 Gbps)



# The INFN - IGNITE initiative



National initiative fundend by **INFN**

- 14 INFN institutes
- 70 people involved (physicist and engineers)
- P.I. Adriano Lai (INFN Cagliari)

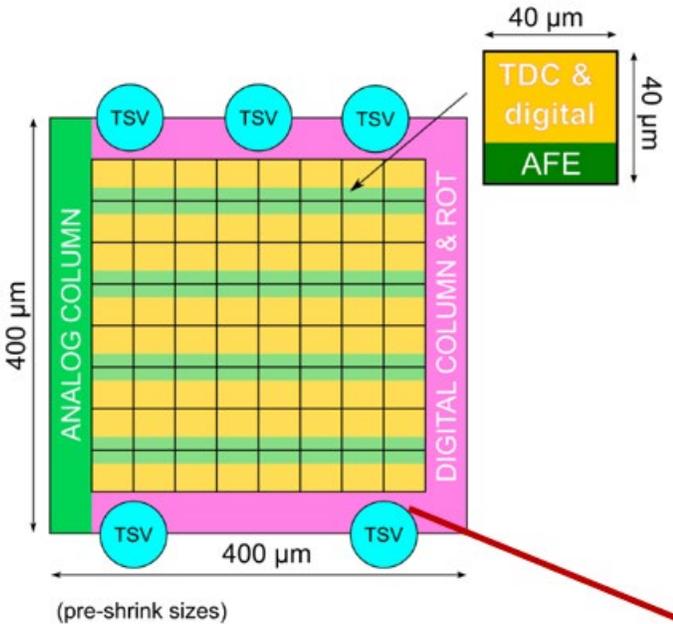
GOAL: DEVELOP A TRACKING SYSTEM  
SUITABLE FOR HIGH LUMINOSITY CONDITIONS

- 1) Integrated system composed by a hybrid 28nm CMOS ASIC and pixel Sensor MATRIX
- 2) Readout ASIC for HIGH-BANDWIDTH optical data transmission
- 3) Take advantage of the experience obtained from the previous R&D projects (Timespot, Falaphel etc..)

considering all the challenges in realizing such a device

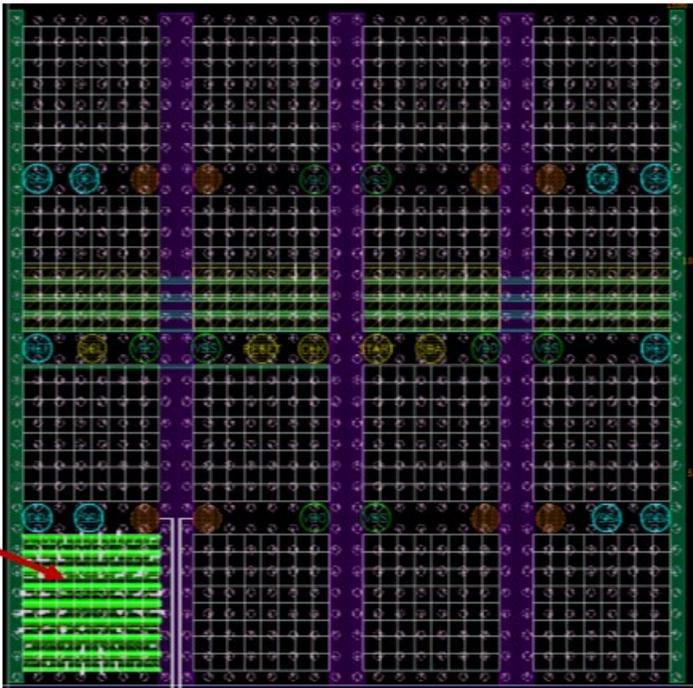
- Obtain uniform timing performance over a large area
  - Minimize power consumption
  - Distribute data to the read out
  - Etc.
- 4) Explore innovative 3D technologies and vertical connections (TSVs, Face2Face or Face2Back bonding)

# The IGNITE ASIC concept

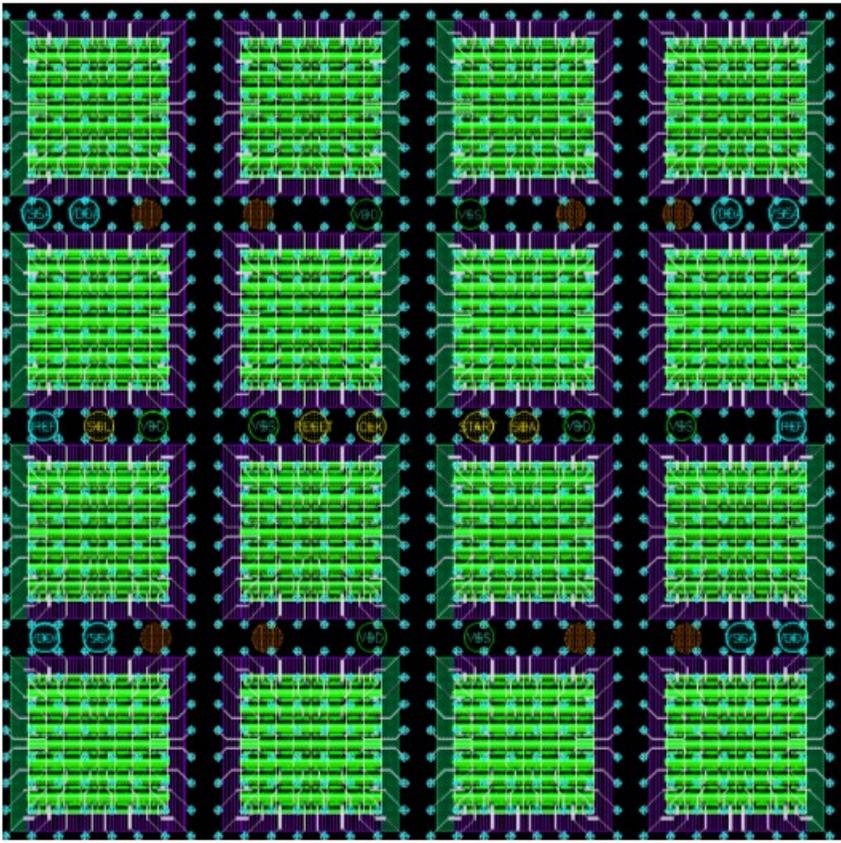


## ELEMENTARY REPETITION UNIT 8X8 PIXEL

- Each pixel has 36μm pitch and AFE + TDC
- Make space for the TSV
- Plls for clock distribution in the digital space between tiles



Example of 32x32 ASIC for 45 μm pitch Sensor



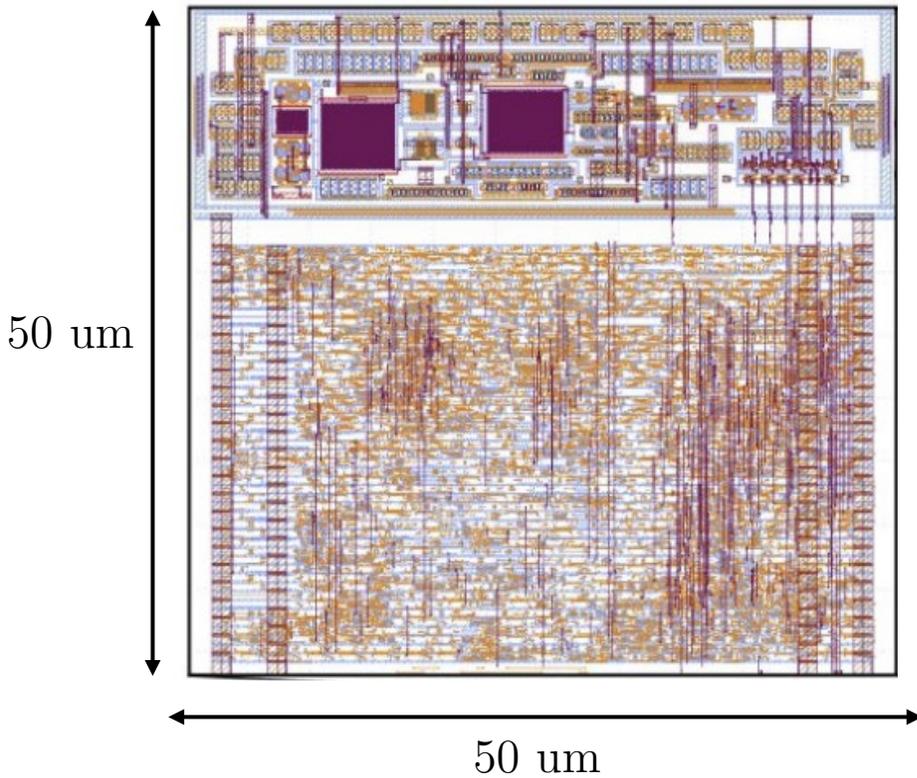
Example of 32x32 ASIC for 55 μm pitch Sensor

Same repetition unit with different redistribution layer

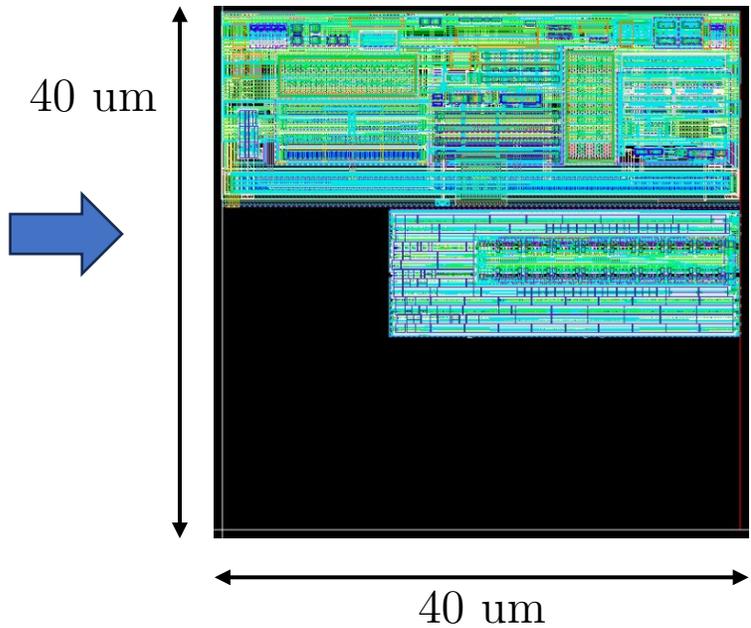
Higher pitch (110μm, 165μm etc.) can be obtained by channel masking

# RESULTS: IGNITE ASIC PIXEL

## TIMESPOT1 PIXEL



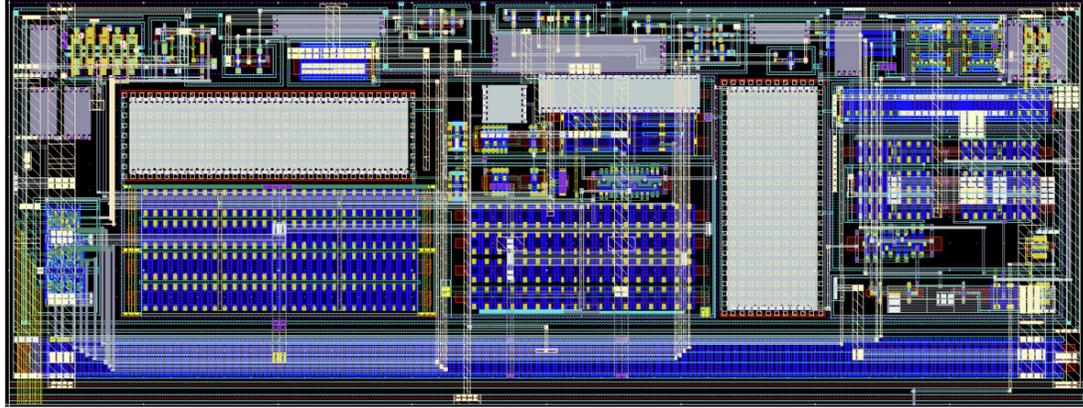
## IGNITE PIXEL



\* PRE-SHRINK SIZES

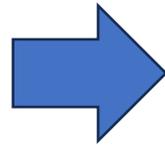
- The pixel Fundamental cells (AFE and TDC) have been completely redesigned using the new 28nm technology (HPC → HPC+)
- The experience gained with the TIMESPOT1 ASIC was fundamental to speedup the process
- Several improvements in area, power consumption and performance

# RESULTS: PIXEL AFE



## TIMESPOT1 AFE

- CSA inverted based with double Krummenacher feedback + dual Stage Discriminator
- Discrete time DC Offset compensation (global threshold and baseline)
- Issue with the Offset compensation but average performance around 60ps for 2fC charge injection with 100fF Sensor Capacitance



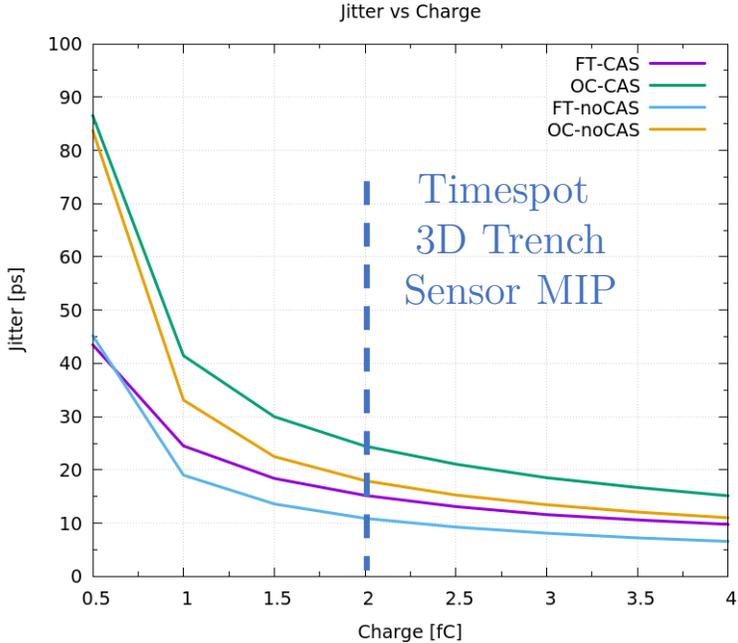
## IGNITE Analog Front-Ends

- Several topologies investigated ( CSA, Common Gate TIA, Cascode TIA..etc)
- 4 different flavors simulated and with finalized design (Layout + Post Layout Simulations)
  1. Cascoded Inverter with Fine DAC threshold tuning (**FT-CAS** )
  2. Cascoded Inverter with enhanced Offset Compensation (**OC-CAS**)
  3. No-Cascode Inverter with Fine DAC threshold tuning (**FT-noCAS** )
  4. No-Cascode Inverter with enhanced Offset Compensation (**OC-noCAS**)

### Specifics:

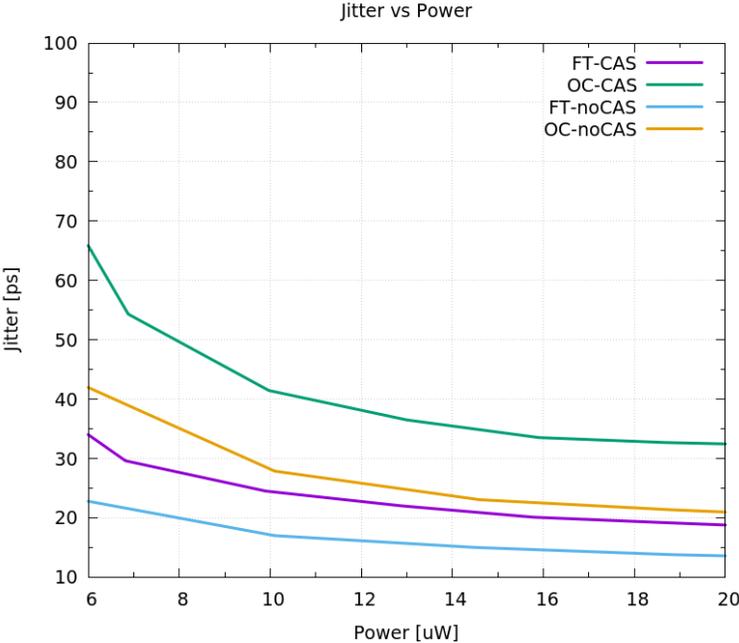
- LAYOUT AREA = 40um x 15um
- Local Charge injection circuit
- Programmable Power : 4uW → 21 uW
- Programmable TOT: e.g., 10ns → 160ns

# RESULTS: PIXEL AFE (post layout simulations)



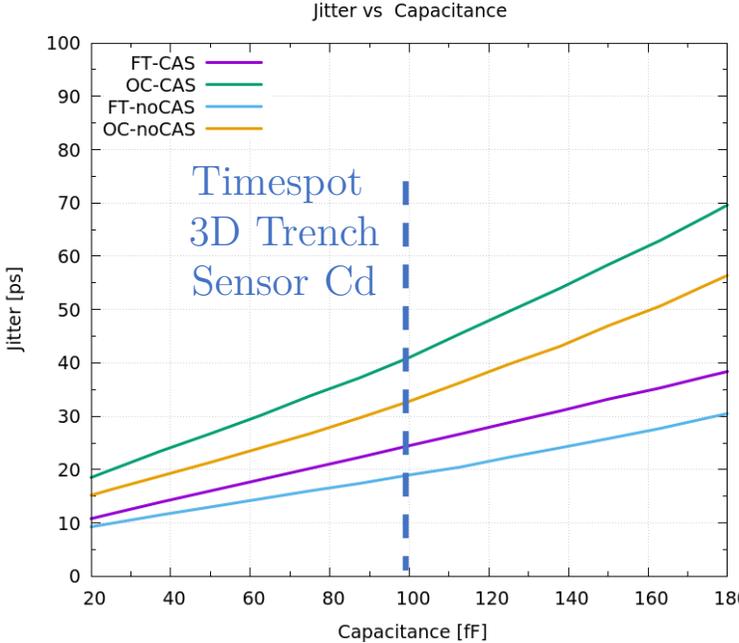
Jitter Vs Charge  
evaluated with:

Cd = 100fF  
 Power = 10.8 uW  
 Discharge Current = 100nA  
 Vth ~ 30mV



Jitter Vs Power  
evaluated with:

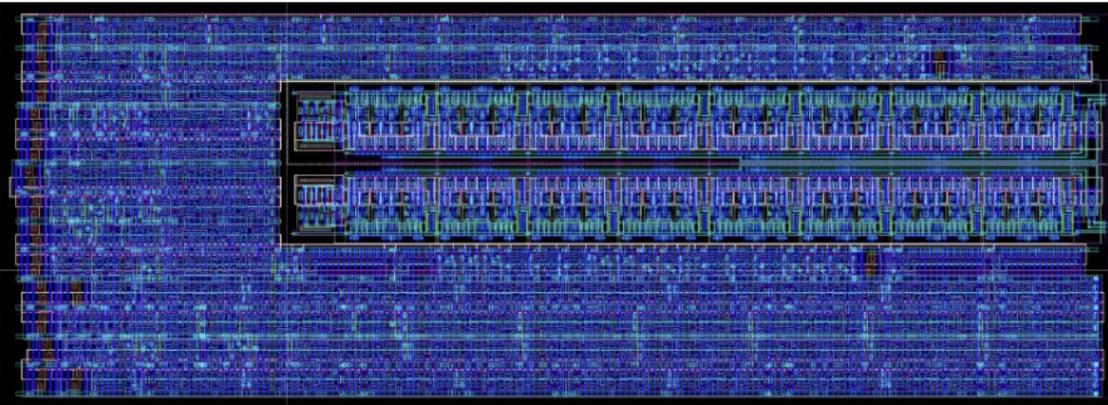
Cd = 100fF  
 Discharge Current = 100nA  
 Vth ~ 30mV  
 Qin = 1fC



Jitter Vs Capacitance  
evaluated with:

Qin = 1fC  
 Power = 10.8uW  
 Discharge Current = 100nA  
 Vth ~ 30mV

# RESULTS: PIXEL TDC



## TIMESPOT1 TDC

- VERNIER ARCHITECTURE
- 2 DCO with frequency ~ 1GHz
- DCO switched off after measure
- Time resolution the depends on the difference in period of the 2 DCO
- TA (~ 20ps), TOT (~ 1ns)
- TIMESPOT1 RTL DESIGN

### Timespot TDC Power Cons.

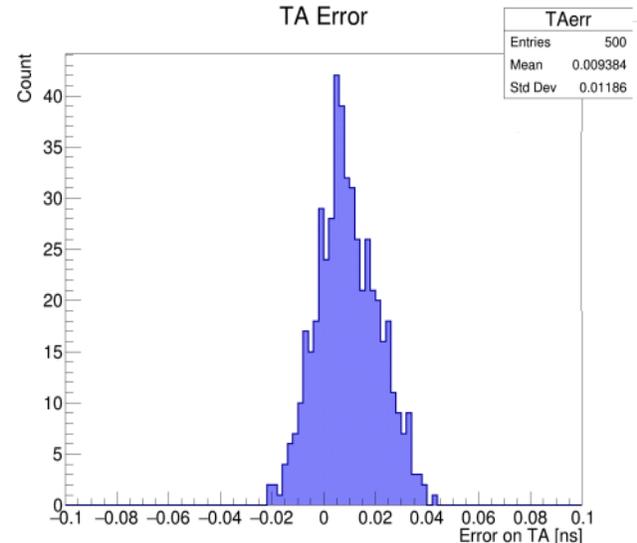
TDC power	μW
IDLE	20.7
Calibration	552
DAQ 3 MHz	175
DAQ 1 MHz	69.3
DAQ 500 kHz	45.5
DAQ 100 kHz	25.7

## IGNITE TDC

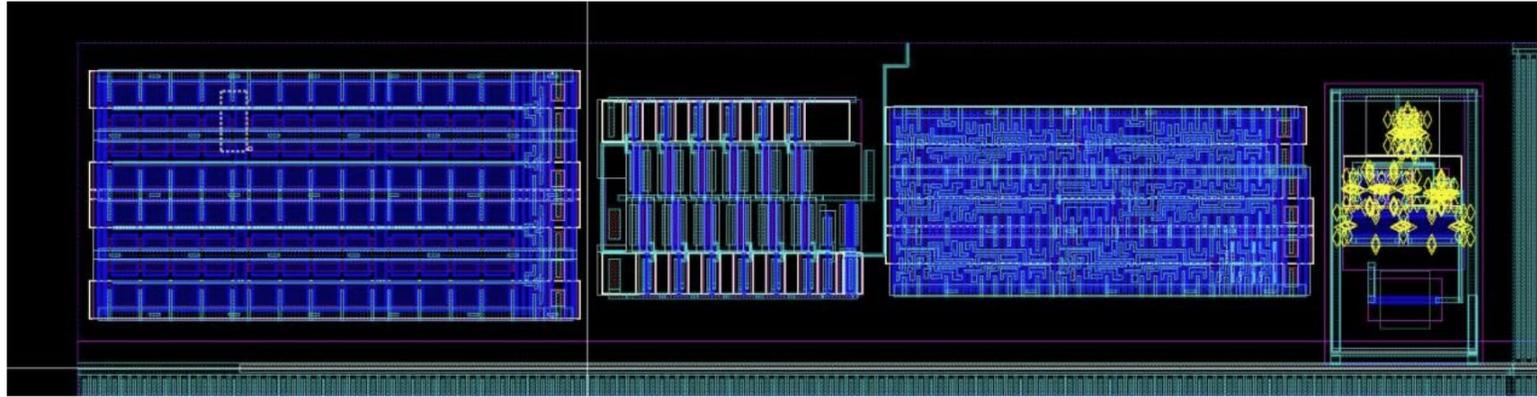
- SAME VERNIER ARCHITECTURE DESIGNED COMPLETELY FULL CUSTOM (Area 27um x 10um)
- DCO WITH 16 DELAY UNITS
  - Period range: 780ps → 900ps
  - Period tuning: Coarse (~50ps), Fine (3ps)
  - DCO jitter ~ 1ps
- MEASURE OF TA with resolution ~ **12ps rms (POST LAYOUT SIMULATION)**

### IGNITE TDC Power Cons.

TDC status	Current
OFF	0.5 μA
IDLE	1.3 μA
Calib. DCO (Istant. @1.12 GHz)	98 μA
RUN (4.5 MHz)	28.3 μA
RUN (1.0 MHz)	7.5 μA
RUN (500 kHz)	3.9 μA
RUN (333 kHz)	3.0 μA
RUN (200 kHz)	2.3 μA



# RESULTS: IGNITE PLL



- PLL (Phased Locked Loop) designed in order to provide an internal reference clock with a static phase with respect to an external clock
- Based on a starved DCO with 3 different starving schemes (static, DAC and external)
- Core Area: 30um x 6um
- Area with Filter : 433um x 15.6 um
- Lock frequency : 40 MHz
- **POST SIMULATION:** power consumption 50uW, jitter filtering from 14ps (input) to 1.9ps (output)

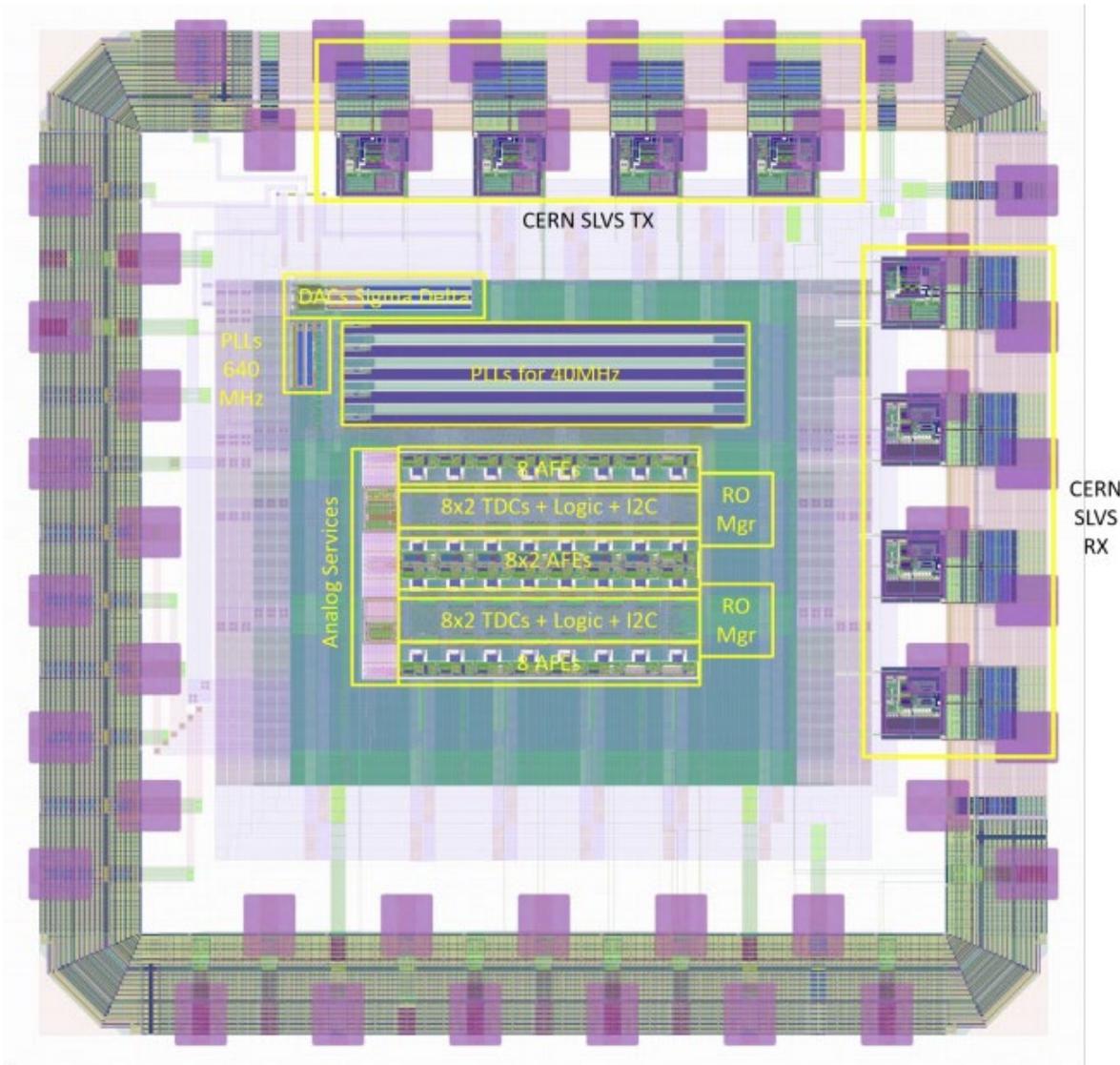
# RESULTS: IGNITE0 TEST CHIP

## IGNITE0 mini@SIC

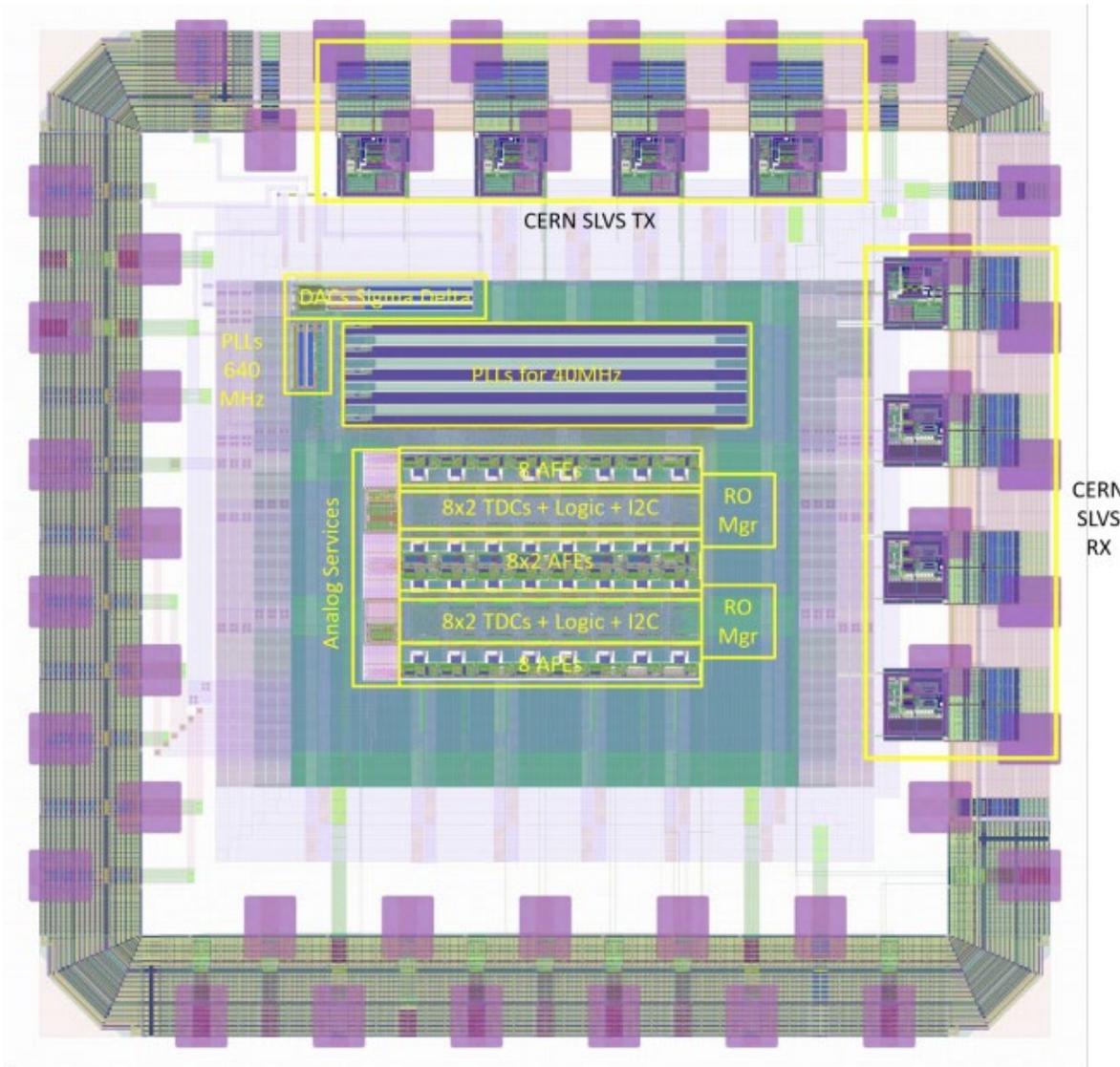
- Submitted in July '23
- Expected in November '23

### Contains:

- Half Tile 8x4 ( Half repetition unit)
- 32 AFE channels (All different flavours)
- 32 TDCs
- PLLs for clock generation/filtering (40MHz and 640MHz)
- DACs
- Readout Managers
- I2C interfaces for controls and configuration



# RESULTS: IGNITE0 TEST CHIP



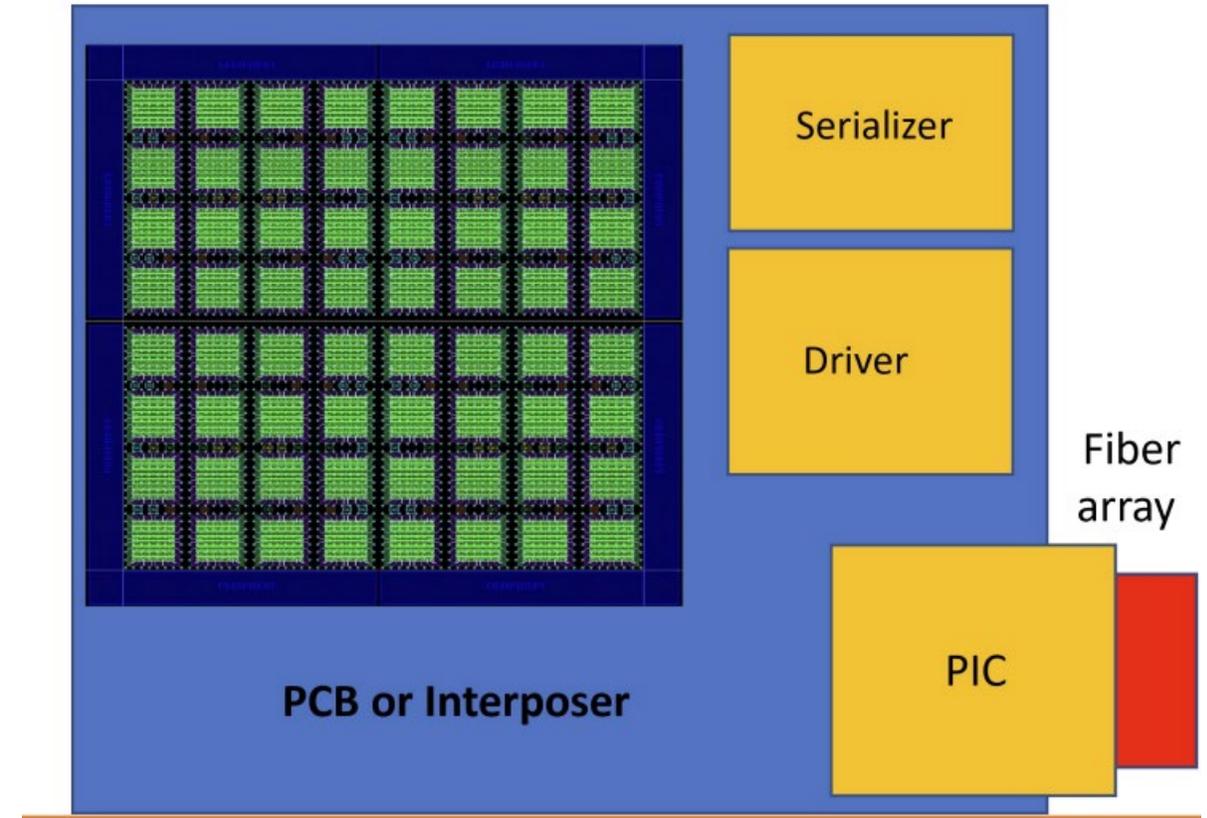
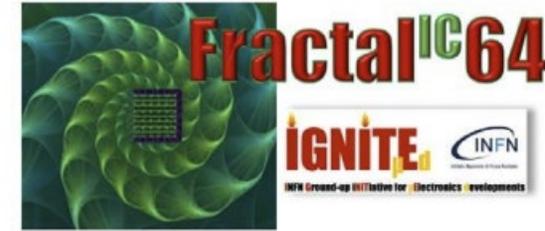
## IGNITE0 mini@SIC

Some of the test we will be able to do:

- Each pixel AFE can be pulsed individually using the Charge injection cell (measure jitter vs Charge), (measure jitter vs power)
- Each AFE is connected to a “Sensor Cell” that allow to change the capacitance load (from 12.5fF to 187fF) at the input of the amplifier (measure jitter vs capacitance)
- TDCs can be pulsed through the AFE but also from outside using a FAST-IN LVDS input (TDC performance scanning the phase with high accuracy)
- Evaluate PLLs performance using loopback connection

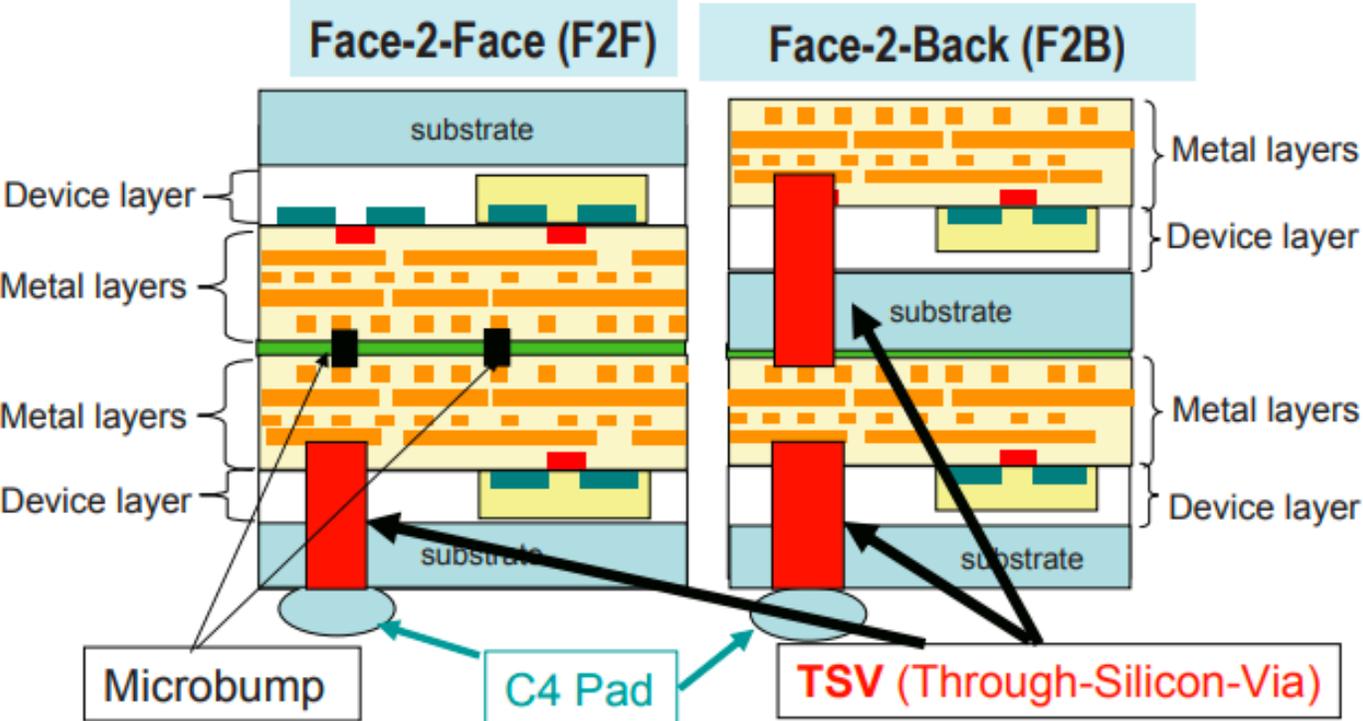
# IGNITE Conclusions and Perspectives:

- The IGNITE initiative is currently working for develop a tracking system for High luminosity environments
- We have submitted a first prototype (IGNITE0) that contains half of the repetition unit that we want to use as a building block for a larger chip
- We are currently working on the test PCB that will allow us to test IGNITE0
- **Next step development of ASIC “Fractal\_IC\_64”**
  - 64x64 pixels matrix
  - Periphery for test with conventional wire bonding integration



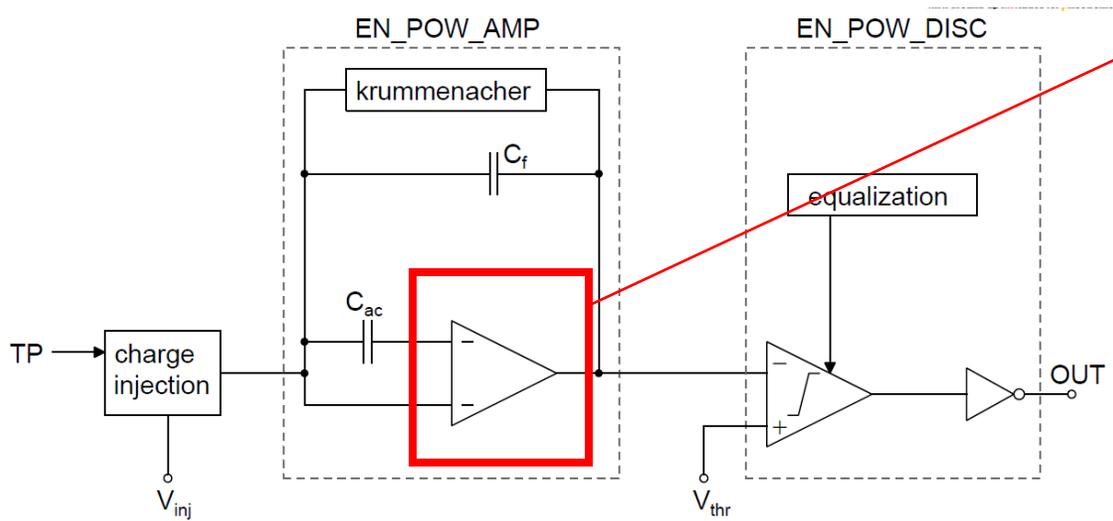
THANK YOU

# IGNITE: 3D/Vertical integration techniques



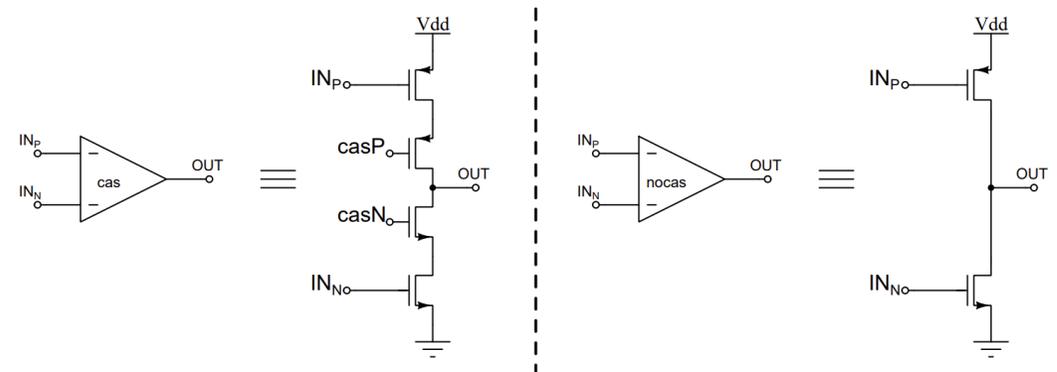
- 3D INTEGRATION: vertical interconnection of different active layers (different ASICs for example) using TSV (Through Silicon Vias)
- Possibility of eliminate the inactive areas due to wire-bondings and enable “abutting”
- Each layer can be assigned to a particular function, e.g. ( Front-end, Clock distribution, data merging)

# IGNITE AFE schematic:



## Two Core Amplifier solution:

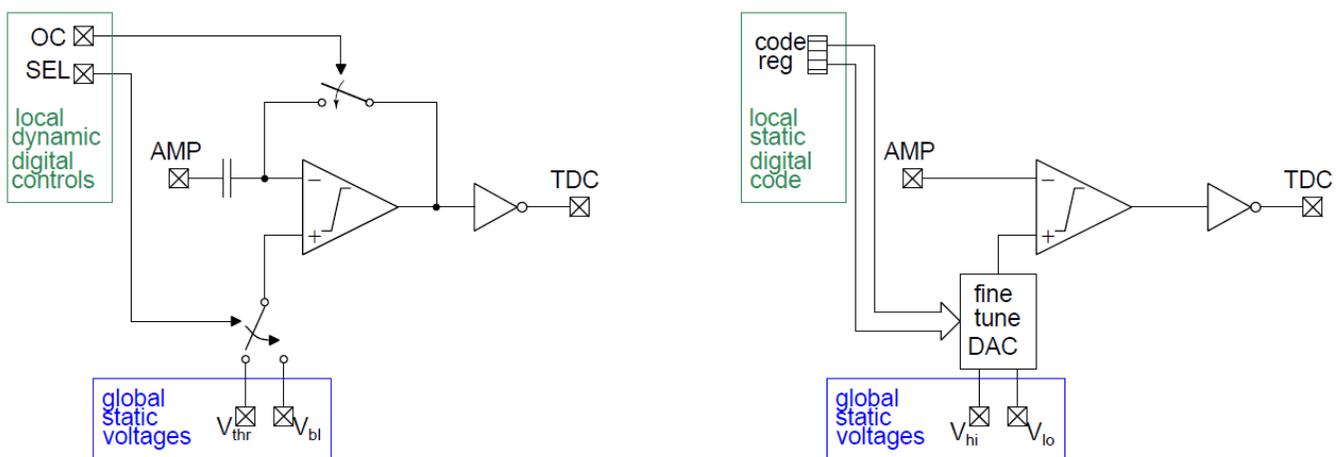
- Cascoded Inverter
- No-Cascode inverter



## General architecture of the Analog Front-End

- Single Krummenacher Feedback
- AC coupling
- Dual Stage Discriminator

## Two channel equalization solution: Offset Compensation, Finetune DAC

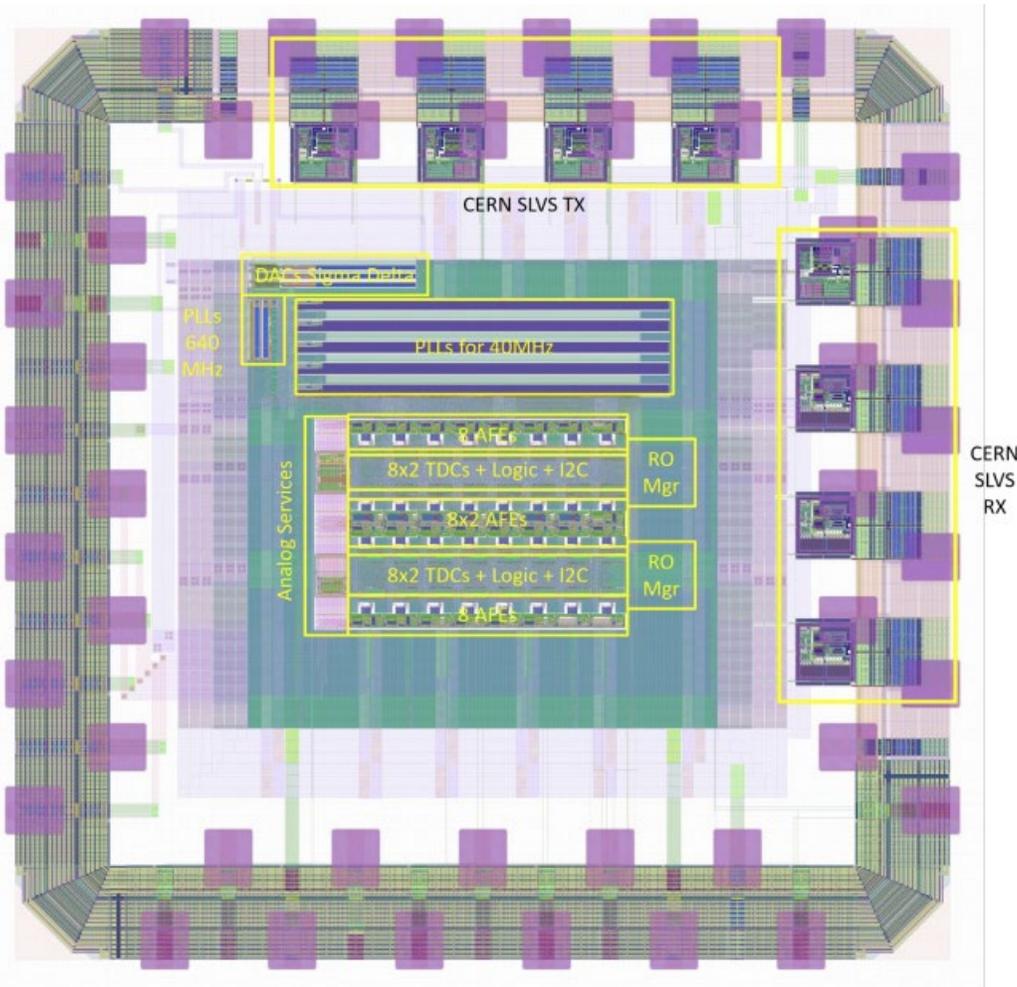


# RESULTS: IGNITE0 TEST CHIP

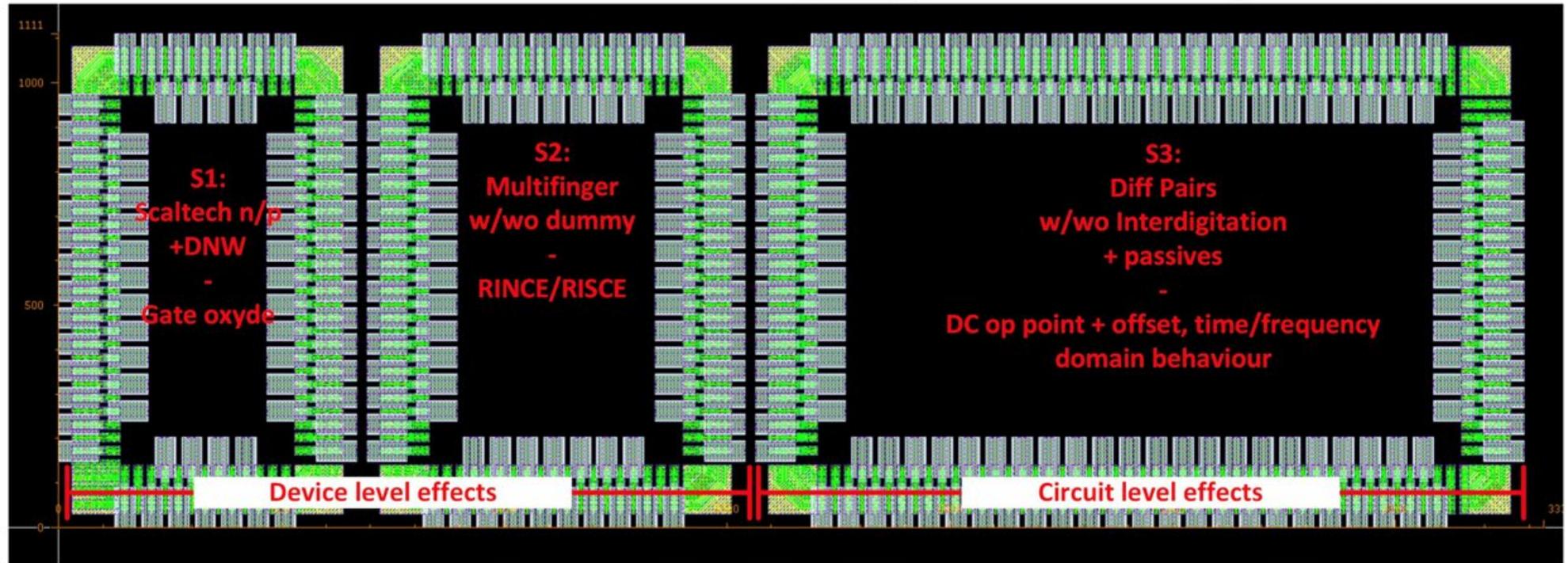
## IGNITE0 mini@SIC

### READOUT SYSTEM:

- One 16-word depth FIFO for each 8x2 block
- Each event is a 49-bit word that includes all the info (Vernier counters, TOT, Coarse Timestamp/Bxid, Event type, pixel Address, FIFO Status)
- Data not optimized for bandwidth (testing purposes)
- Data out on two differential lines @ 640 Mb/s
- Max event rate per output line/FIFO => ~ 12.5 MHz
- Max event rate per pixel ~ 780 KHz



# IGNITE radiation hardness of 28nm HPC+:



## IGNITE RAD-CHIP

- Submitted in April, samples arriving
- PCB for testing under preparation
- Irradiation test scheduled in Padua